



## **OFC 2024**



## OFC 2024 Makes Its Return to San Diego

The Optical Fiber Communication Conference and Exhibition (OFC), returning to the San Diego Convention Center March 24 to 28, will feature a hybrid format that allows attendees to see both in-person and virtual talks. Those who attend in-person will be able to explore an event hosting more than 13,000 participants from more than 70 countries and featuring more than 540 companies on the exhibition floor.

# **Read More**



## .: Featured Exhibitors

#### **Fastest Optical Wavelength Meter**

#### From: Bristol Instruments Inc.

The 828 Series High-Speed Optical Wavelength Meter from Bristol Instruments, with a 1-kHz continuous measurement rate, reduces test times in the production of tunable transmitter lasers. Its time resolution of 1 ms also provides the most detailed and rapid wavelength characterization of tunable laser transceivers. The rugged design of the 828 Series is backed by Bristol Instruments' 5-year warranty on all parts and labor ensuring long-term reliable operation. Visit us at Booth #4617.



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## **Quantum Light Sources**

## From: OZ Optics Limited

OZ Optics is excited to introduce a new line of waveguide-based quantum entangled-photon sources with unprecedented brightness. A compensation-free and self-balanced interferometric scheme is implemented to produce high-quality polarization entanglement and hyperentanglement. Aimed at emerging quantum photonics industries as well as ambitious researchers, these compact sources with built-in pump lasers are presented as plug-and-play and integrable devices operating at visible and telecom wavelengths. Visit us at Booth #3012.



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## Industrial Laser Monitoring System

## From: DataRay Inc.

DataRay's Industrial Laser Monitoring System (ILMS) is specially designed for profiling focused, high-power industrial lasers. It combines reimaging/magnification optics, a polarization preserving beam sampler, and a DataRay beam profiler to measure small beam waists which would otherwise damage a traditional profiler. Magnification of the focused beam allows full pixel-by-pixel 2D measurements of beam spots as small as a few microns; software ensures results do not require post processing or corrections. Visit us at Booth #1912.



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